M.TECH/VLSI/1ST SEM /VLSI 5103/2015 2015

Microelectronics Technology and IC Fabrication (VLSI 5103)

Time Allotted: 3 hrs

Full Marks: 70

Figures out of the right margin indicate full marks.

Candidates are required to answer Group A and any 5 (five) from Group B to E, taking at least one from each group.

Candidates are required to give answer in their own words as far as practicable.

		(Multiple Chr	Group - A		
1	Choose the corr		oice Type Questions)	10 x 1=10	
	Choose the correct alternatives for the following: 10 x (i) The active components in an Integrated Circuit are				
	(a) resistors	(b) capacitors	(c) transistors	(d) all of the above.	
	(ii) Electronic grade silicon has a purity level at least of about				
	(a) 98%	(b) 99%	(c) 99.9999%	(d) 99.999999%.	
		tching occurs in			
	(a) all directions		(b) in a particular direction		
	(c) in two directions		(d) none of the above.		
	(iv) Optical mas	sking is used for			
	(a) patte	ern transfer	(b) protection		
	(c) cleaning		(d) none of the above.		
	(v) The liquid s	ource employed for ba	sic diffusion of Phosphoro	us in Silicon is	
	(a) P ₂ O ₅		(b) PH ₃		
	(c) POCI	3	(d) PH ₄ .		
AND MAKE THE	(vi) For deposition of SiO ₂ over polysilicon or in order to obtain excellent SiO ₂ film uniformity which of the of the following chemical reactions are normally employed?				
	(a) Oxygen reduction of SiH ₄ at 450°C				
	(b) Oxygen reduction of PH ₃ at 450°C				
	(c) Decomposition of Si(OC ₂ H ₅) ₄ Tetraethylorthosilicate at 700°C				
	(d) Read	ting dichlorosilane, SiC	l ₂ H ₂ with nitrous oxide at	900°C.	
	(vii) VPE stand	s for			
	(a) vapo	our phase epitaxy	(b) vacuum ph		
		ur phase etching	(d) none of the	above.	

	st is acom			
(a) radiation-sensitive		(b) radiation	(b) radiation-insensitive	
(c) radia	ative	(d) non-radia	(d) non-radiative .	
(ix) Sputtering	is a proce	ess		
(a) physical	(b) chemical	(c) mechanical	(d) none of the above.	
(x) Metallizatio	n is used for			
(a) interconnection		(b) packaging		
(c) prote		(d) all of the above.		
		Group - B		
2.(a) Mention the	uses of SiO ₂ in the IC fa	brication industry.		
(b) Differentiate	between dry and wet	oxidation. Write down t	the corresponding chemical	
equations. Exp	plain with a suitable so		al horizontal tube oxidation	
furnace set-up			4+(1+2+5) = 12	
2 (a) Dacariba tui	th mitable ashamatic	diagram the processes	carried out for growth of	
	on float zone techniqu		carried out for growdr or	
in production	on of very pure single		nique & Czochralski method ss the neutron irradiation horous. 6+6=12	
		Group – C		
4.(a) What is wet of wet chemical et		at are the characteristics	of an ideal etchant used for	
(b) Discuss Buffe	ered Oxide Etching, its	advantages and limitation	ons. (1+5)+6=12	
		nguish between vacancy	e schematic diagram of an y diffusion and interstitial	
			7 1/2 1/60	
	s diffusion equation? I dopant diffusion.	Find the solution to the F	ick's diffusion equation for	

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Group - D

- 6.(a) State the advantages and disadvantages of ion-implantation.
 - (b) Use the LSS theory to calculate the implant dose required to give a peak dopant concentration of 5×10^{18} boron atoms cm⁻³ in an n-type Si, doped with 10^{15} phosphorous atoms cm⁻³when boron is implanted at 200 keV into Si. Given the lateral straggle for boron ions at 200 keV is 0.086 micron.

7+5=12

- 7.(a) Write down the chemical equations governing the deposition of SiO_2 and Si_3N_4 from (i) silane (ii) dichlorosilane
 - (b) What is sputtering? How is it advantageous as compared to the different evaporation techniques used in film depositions?

8+4=12

Group - E

- 8.(a) List the properties that a material must have to be useful as an interconnect.
 - (b) What do you mean by aluminium junction spiking? Discuss how it can be overcome.

4+(5+3)=12

- 9.(a) Distinguish between CMOS & BiCMOS technologies. Draw the cross sectional structure of a CMOS inverter.
- (b) Discuss the fabrication sequences of Ga As MESFET. Mention some important features of Ga As MESFET.

8+4=12